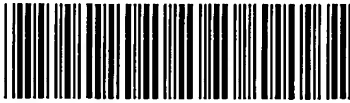


**Search Notes**

Application/Control No.

10/533,349

Examiner

Mohamed Charioui

Applicant(s)/Patent under  
Reexamination

FARRELL ET AL.

Art Unit

2857

**SEARCHED**

Class	Subclass	Date	Examiner
702	8, 40, 49, 57, 60, 64, 65	12/5/2006	MC
702	75, 79	12/5/2006	MC
702	80, 107	12/5/2006	MC
702	179, 182	12/5/2006	MC
702	183, 184	12/5/2006	MC
702	189	12/5/2006	MC
372	20	12/5/2006	MC
372	29.01	12/5/2006	MC
374	183	12/5/2006	MC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East: (degradat\$6 with tun\$6 with laser) and calibrat\$6 and (structure with (laser or diode\$1)) and wavelength and	12/5/2006	MC
(current with diode\$1)	12/5/2006	MC
East: (degradat\$6 with tun\$6 with laser) and (calibrat\$6 or adjust) and (laser or diode\$1) and wavelength and	12/5/2006	MC
(current with diode\$1)	12/5/2006	MC
IEEE search	12/5/2006	MC
IEEE: Search by inventor's name	12/5/2006	MC